

# **HIGH-SPEED** 8K x 16 DUAL-PORT STATIC RAM

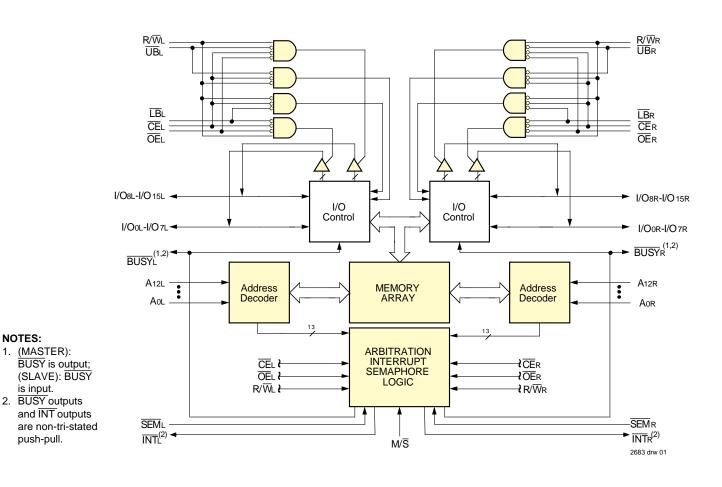
## **FEATURES:**

- True Dual-Ported memory cells which allow simultaneous access of the same memory location
- High-speed access
  - Military: 20/25/35/55/70ns (max.)
  - Commercial: 15/17/20/25/35/55ns (max.)
- Low-power operation
- IDT7025S Active: 750mW (typ.) Standby: 5mW (typ.) – IDT7025L
  - Active: 750mW (typ.)
  - Standby: 1mW (typ.)
- Separate upper-byte and lower-byte control for multiplexed bus compatibility

FUNCTIONAL BLOCK DIAGRAM

IDT7025 easily expands data bus width to 32 bits or more using the Master/Slave select when cascading more than one device

- $M/\overline{S} = H$  for  $\overline{BUSY}$  output flag on Master  $M/\overline{S} = L$  for  $\overline{BUSY}$  input on Slave
- **Busy and Interrupt Flags**
- On-chip port arbitration logic
- Full on-chip hardware support of semaphore signaling between ports
- Devices are capable of withstanding greater than 2001V electrostatic discharge
- Fully asynchronous operation from either port
- Battery backup operation-2V data retention
- TTL-compatible, single 5V (±10%) power supply
- Available in 84-pin PGA, 84-pin quad flatpack, 84-pin PLCC, and 100-pin Thin Quad Plastic Flatpack
- Industrial temperature range (-40°C to +85°C) is available, tested to military electrical specifications



The IDT logo is a registered trademark of Integrated Device Technology Inc.

## MILITARY AND COMMERCIAL TEMPERATURE RANGES

#### **OCTOBER 1996**

©1996 Integrated Device Technology, Inc. For latest information contact IDT's web site at www.idt.com or fax-on-demand at 408-492-8391.

1.

6.16

## **DESCRIPTION:**

The IDT7025 is a high-speed 8K x 16 Dual-Port Static RAM. The IDT7025 is designed to be used as a stand-alone 128K-bit Dual-Port RAM or as a combination MASTER/SLAVE Dual-Port RAM for 32-bit or more word systems. Using the IDT MASTER/SLAVE Dual-Port RAM approach in 32-bit or wider memory system applications results in full-speed, error-free operation without the need for additional discrete logic.

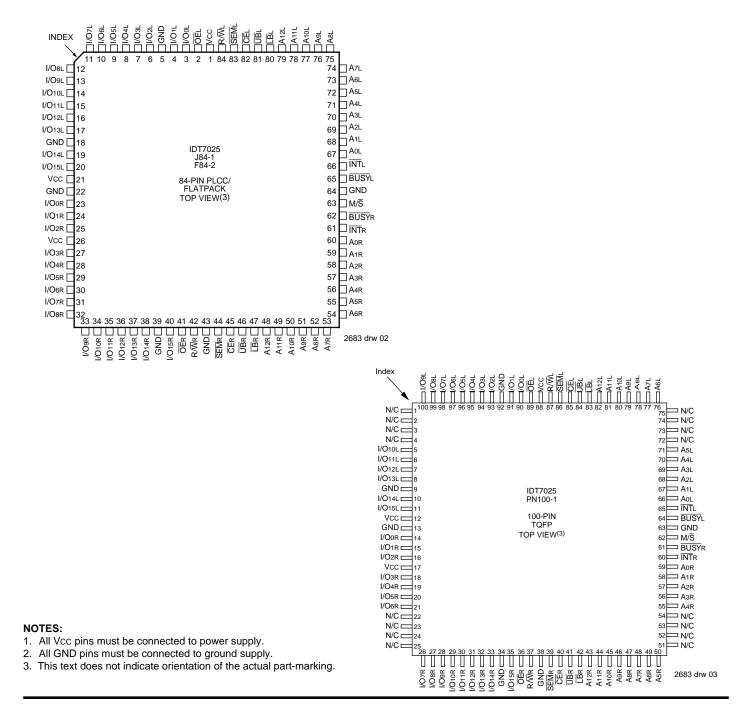
This device provides two independent ports with separate control, address, and I/O pins that permit independent, asynchronous access for reads or writes to any location in memory. An automatic power down feature controlled by Chip

## **PIN CONFIGURATIONS** (1,2)

Enable  $(\overline{CE})$  permits the on-chip circuitry of each port to enter a very low standby power mode.

Fabricated using IDT's CMOS high-performance technology, these devices typically operate on only 750mW of power. Low-power (L) versions offer battery backup data retention capability with typical power consumption of  $500\mu$ W from a 2V battery.

The IDT7025 is packaged in a ceramic 84-pin PGA, an 84pin quad flatpack, an 84-pin PLCC, and a 100-pin TQFP. Military grade product is manufactured in compliance with the latest revision of MIL-STD-883, Class B, making it ideally suited to military temperature applications demanding the highest level of performance and reliability.



## PIN CONFIGURATIONS (CONT'D) (1,2)

	63	61	60	58	55	54	51	48	46	45	42
11	I/O7L	I/O5L	I/O4L	I/O2L	I/Ool	ŌĒL	SEML	ĹΒL	A11L	A10L	A7L
	66	64	62	59	56	49	50	47	44	43	40
10	I/O10L	I/O8L	I/O6L	I/O3L	I/O1∟	UBL	CEL	A9L	A8L	A5L	
	67	65			57	53		41	39		
09	I/O11L	I/O9L			GND	Vcc		A6L	A4L		
	69	68	1					1		38	37
08	I/O13L	I/O12L						A3L	A2L		
	72	71	73						33	35	34
07	I/O15L	I/O14L	Vcc			IDT702	5		BUSY∟	Aol	ĪNTL
	75	70	74			G84-3			32	31	36
06	I/Oor	GND	GND			84-PIN P OP VIEV			GND	M/S	A1L
	76	77	78						28	29	30
05	I/O1R	I/O2R	Vcc						Aor	INTR	BUSYR
	79	80							L	26	27
04	I/O3R	I/O4R								A2R	A1R
	81	83	-		7	11	12	]		23	25
03	I/O5R	I/O7R			GND	GND	SEMR			A5R	Азr
	82	1	2	5	8	10	14	17	20	22	24
02	I/O6R	I/O9R	I/O10R	I/O13R	I/O15R	R/WR	UBR	A11R	A8R	A6R	A4R
	84	3	4	6	9	15	13	16	18	19	21
01	I/O8R	I/O11R	I/O12R	I/O14R	ŌĒR	LBR	CER	A12R	A10R	A9R	A7R
1	A	В	С	D	E	F	G	Н	J	ĸ	L
dex											2683 drw

#### NOTES:

- 1. All Vcc pins must be connected to power supply.
- 2. All GND pins must be connected to ground supply.
- 3. This text does not indicate orientation of the actual part-marking.

## **PIN NAMES**

Left Port	Right Port	Names
CEL	CER	Chip Enable
R/WL	R/WR	Read/Write Enable
OEL	ŌĒR	Output Enable
A0L – A12L	A0R – A12R	Address
I/O0L – I/O15L	I/O0R – I/O15R	Data Input/Output
SEML	SEMR	Semaphore Enable
ŪBL	UBR	Upper Byte Select
LΒL	LBR	Lower Byte Select
INTL	INTR	Interrupt Flag
BUSYL	BUSYR	Busy Flag
Μ	I/S	Master or Slave Select
V	СС	Power
GI	ND	Ground
		2683 tbl 01

## RECOMMENDED OPERATING TEMPERATURE AND SUPPLY VOLTAGE

Grade	Ambient Temperature	GND	Vcc
Military	–55°C to +125°C	0V	$5.0V \pm 10\%$
Commercial	0°C to +70°C	0V	$5.0V \pm 10\%$
		•••	

2683 tbl 02

3

6.16

#### TRUTH TABLE I – NON-CONTENTION READ/WRITE CONTROL

		Inpu	uts <sup>(1)</sup>			Out	outs	
CE	R/W	ŌĒ	ŪB	LB	SEM	I/O8-15	I/O0-7	Mode
Н	Х	Х	Х	Х	Н	High-Z	High-Z	Deselected: Power Down
Х	Х	Х	Н	Н	Н	High-Z	High-Z	Both Bytes Deselected
L	L	Х	L	Н	Н	DATAIN	High-Z	Write to Upper Byte Only
L	L	Х	Н	L	Н	High-Z	DATAIN	Write to Lower Byte Only
L	L	Х	L	L	Н	DATAIN	DATAIN	Write to Both Bytes
L	Н	L	L	Н	Н	DATAOUT	High-Z	Read Upper Byte Only
L	Н	L	Н	L	Н	High-Z	DATAOUT	Read Lower Byte Only
L	Н	L	L	L	Н	DATAOUT	DATAOUT	Read Both Bytes
Х	Х	Н	Х	Х	Х	High-Z	High-Z	Outputs Disabled
NOTE:	•			-	•	•	•	2683 tbl 03

1. AOL — A12L are not equal to AOR — A12R.

## TRUTH TABLE II – SEMAPHORE READ/WRITE CONTROL<sup>(1)</sup>

		Inp	uts			Outp	outs	
CE	R/₩	ŌĒ	UB	LB	SEM	I/O8-15	I/O0-7	Mode
Н	Н	L	Х	Х	L	DATAOUT	DATAOUT	Read Semaphore Flag Data Out
Х	Н	Г	Н	Н	L	DATAOUT	DATAOUT	Read Semaphore Flag Data Out
Н	ſ	Х	Х	Х	L	DATAIN	DATAIN	Write I/Oo into Semaphore Flag
Х	ſ	Х	Н	Н	L	DATAIN	DATAIN	Write I/Oo into Semaphore Flag
L	Х	Х	L	Х	L	—	—	Not Allowed
L	Х	Х	Х	L	L	—	—	Not Allowed

NOTE:

1. There are eight semaphore flags written to via I/Oo and read from I/Oo - I/O15. These eight semaphores are addressed by Ao - A2.

## ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

Symbol	Rating	Commercial	Military	Unit
Vterm <sup>(2)</sup>	Terminal Voltage with Respect to GND	-0.5 to +7.0	-0.5 to +7.0	V
ΤΑ	Operating Temperature	0 to +70	-55 to +125	°C
TBIAS	Temperature Under Bias	–55 to +125	–65 to +135	°C
Тѕтс	Storage Temperature	-55 to +125	-65 to +150	°C
Ιουτ	DC Output Current	50	50	mA

#### NOTES:

- 1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 2. VTERM must not exceed Vcc + 0.5V for more than 25% of the cvcle time or 10ns maximum, and is limited to ≤ 20 mA for the period over VTERM ≥ Vcc + 0.5V.

## RECOMMENDED DC OPERATING **CONDITIONS**

Symbol	Parameter	Min.	Тур.	Max.	Unit
Vcc	Supply Voltage	4.5	5.0	5.5	V
GND	Supply Voltage	0	0	0	V
Vін	Input High Voltage	2.2	—	6.0 <sup>(2)</sup>	V
VIL	Input Low Voltage	-0.5 <sup>(1)</sup>	_	0.8	V

NOTES:

1. VIL  $\geq$  -1.5V for pulse width less than 10ns.

2. VTERM must not exceed Vcc + 0.5V.

## CAPACITANCE<sup>(1)</sup>

#### (TA = +25°C, f = 1.0MHz)TQFP ONLY

Symbol	Parameter	Conditions <sup>(2)</sup>	Max.	Unit
CIN	Input Capacitance	VIN = 3dV	9	pF
Соит	Output Capacitance	Vout = 3dV	10	pF

#### NOTES:

2683 tbl 05

2683 tbl 07

2683 tbl 04

<sup>1.</sup> This parameter is determined by device characterization but is not production tested.

<sup>2. 3</sup>dV references the interpolated capacitance when the input and output signals switch from 0V to 3V or from 3V to 0V.

# DC ELECTRICAL CHARACTERISTICS OVER THE OPERATING TEMPERATURE AND SUPPLY VOLTAGE RANGE (Vcc = $5.0V \pm 10\%$ )

			IDT7	IDT7025S IDT7025L		)25L	
Symbol	Parameter	Test Conditions	Min.	Max.	Min.	Max.	Unit
LI	Input Leakage Current <sup>(1)</sup>	VCC = 5.5V, $VIN = 0V$ to $VCC$	_	10	_	5	μΑ
Ilo	Output Leakage Current	$\overline{CE} = VIH$ , VOUT = 0V to VCC	_	10		5	μΑ
Vol	Output Low Voltage	IOL = 4mA	_	0.4		0.4	V
Voн	Output High Voltage	Іон = -4mA	2.4		2.4	—	V

NOTE:

1. At Vcc  $\leq$  2.0V input leakages are undefined.

2683 tbl 08

## DC ELECTRICAL CHARACTERISTICS OVER THE OPERATING TEMPERATURE AND SUPPLY VOLTAGE RANGE<sup>(1)</sup> ( $Vcc = 5.0V \pm 10\%$ )

					7025	-		5X17	7025	5X20	7025	5X25	
		Test			Com'l.			I. Only					
Symbol	Parameter	Condition	Versi	on	Typ. <sup>(2)</sup>	Max.	Typ. <sup>(2)</sup>	Max.	Тур. <sup>(2)</sup>	Max.	Тур.	<sup>(2)</sup> Max.	Unit
lcc	Dynamic Operating Current	CE"∧"=VIL, Outputs Open SEM = VIH	MIL	S L	_		-	_	160 160	370 320	155 155	340 280	mA
	(Both Ports Active)	$f = fMAX^{(3)}$	СОМ	S L	170 170	310 260	170 170	310 260	160 160	290 240	155 155	265 220	
ISB1	Standby Current (Both Ports — TTL	$\overline{CER} = \overline{CEL} = VIH$ $\overline{SEMR} = \overline{SEML} = VIH$	MIL	S L					20 20	90 70	16 16	80 65	mA
	Level Inputs)	$f = fMAX^{(3)}$	СОМ	S L	20 20	60 50	20 20	60 50	20 20	60 50	16 16	60 50	
ISB2	Standby Current	$\overline{CE}$ "A"=VIL and $\overline{CE}$ "B"=VIL <sup>(5)</sup>	MIL	S	—	—	_	—	95	240	90	215	mA
	(One Port — TTL	Active Port Outputs Open		L	—	_	—	—	95	210	90	180	
	Level Inputs)	$f = fMAX^{(3)}$	СОМ	S	105	190	105	190	95	180	90	170	1
		$\overline{\text{SEM}}_{R} = \overline{\text{SEM}}_{L} = V_{H}$		L	105	160	105	160	95	150	90	140	
ISB3	Full Standby Current (Both Ports — All	Both Ports CEL and CER ≥Vcc - 0.2V	MIL	S L	_		_		1.0 0.2	30 10	1.0 0.2	30 10	mA
	CMOS Level Inputs)		СОМ	S L	1.0 0.2	15 5	1.0 0.2	15 5	1.0 0.2	15 5	1.0 0.2	15 5	
ISB4		CE"A" ≤ 0.2 and         CE"B" ≥ Vcc - 0.2V         SEMR = SEML≥ Vcc - 0.2V	MIL	S L	_	_	_	_	90 90	225 200	85 85	200 170	mA
		$VIN \ge VCC - 0.2V \text{ or}$ $VIN \ge VCC - 0.2V \text{ or}$ $VIN \le 0.2V, \text{ Active Port}$ $Outputs \text{ Open},$ $f = fMAX^{(3)}$	СОМ	S L	100 100	170 140	100 100	170 140	90 90	155 130	85 85	145 120	

NOTES:

1. "X" in part numbers indicates power rating (S or L).

2. Vcc = 5V, TA = +25°C, and are not production tested. Icc dc = 120mA (typ.)

3. At f = fMAX, address and I/O's are cycling at the maximum frequency read cycle of 1/ trc, and using "AC Test Conditions" of input levels of GND to 3V.

4. f = 0 means no address or control lines change.

5. Port "A" may be either left or right port. Port "B" is the opposite from port "A".

## DC ELECTRICAL CHARACTERISTICS OVER THE **OPERATING TEMPERATURE AND SUPPLY VOLTAGE RANGE<sup>(1)</sup>(Cont'd.)** (Vcc = 5.0V ± 10%)

		Test				5X35	_	5X55	Mil.	5X70 Only	
Symbol	Parameter	Condition	Versio	n	Typ. <sup>(2)</sup>	Max.	Typ. <sup>(2)</sup>	Max.	Typ. <sup>(2)</sup>	Max.	Unit
Icc	Dynamic Operating Current	$\frac{\overline{CE}}{\overline{SEM}} = VIL, Outputs Open$ $\overline{SEM} = VIH$	MIL.	S L	150 150	300 250	150 150	300 250	140 140	300 250	mA
	(Both Ports Active)	$f = fMAX^{(3)}$	COM'L.	S L	150 150	250 210	150 150	250 210	—	_	
ISB1	Standby Current (Both Ports — TTL	$\frac{\overline{CE}L = \overline{CE}R = VIH}{\overline{SEM}R = \overline{SEM}L = VIH}$	MIL.	S L	13 13	80 65	13 13	80 65	10 10	80 65	mA
	Level Inputs)	$f = fMAX^{(3)}$	COM'L.	S L	13 13	60 50	13 13	60 50	—	_	
ISB2	Standby Current	$\overline{CE}$ "A"=VIL and $\overline{CE}$ "B"=VIH <sup>(5)</sup>	MIL.	S	85	190	85	190	80	190	mA
	(One Port — TTL	Active Port Outputs Open		L	85	160	85	160	80	160	
	Level Inputs)	$f = fMAX^{(3)}$	COM'L.	S	85	155	85	155	—	_	1
		$\overline{\text{SEM}}R = \overline{\text{SEM}}L = VIH$		L	85	130	85	130	—	—	
ISB3	Full Standby Current (Both Ports — All	Both Ports CEL and CER ≥ Vcc - 0.2V	MIL.	S L	1.0 0.2	30 10	1.0 0.2	30 10	1.0 0.2	30 10	mA
	CMOS Level Inputs)	$\begin{array}{l} \text{VIN} \geq \text{Vcc} & \text{-} 0.2 \text{V or} \\ \overline{\text{VIN}} \leq 0.2 \text{V}, \ \text{f} = 0^{(4)} \\ \overline{\text{SEM}} \text{R} = \overline{\text{SEML}} \geq \text{Vcc} & \text{-} 0.2 \text{V} \end{array}$	COM'L.	S L	1.0 0.2	15 5	1.0 0.2	15 5	_	_	
ISB4	Full Standby Current (One Port — All	$\frac{\overline{CE}}{\overline{CE}} A^{"} \leq 0.2 \text{ and} \\ \overline{CE} B^{"} \geq V CC - 0.2 V^{(5)}$	MIL.	S L	80 80	175 150	80 80	175 150	75 75	175 150	mA
	CMOS Level Inputs)	$\overline{\text{SEM}}$ R = $\overline{\text{SEM}}$ L ≥ VCC - 0.2V									
		VIN $\geq$ VCC - 0.2V or	COM'L.	S	80	135	80	135	—	—	1
		$\label{eq:VIN_second} \begin{split} & \text{VIN} \leq 0.2\text{V}, \\ & \text{Active Port Outputs Open,} \\ & \text{f} = \text{fMAX}^{(3)} \end{split}$		L	80	110	80	110	_		

#### NOTES:

1. "X" in part numbers indicates power rating (S or L).

2. Vcc = 5V, TA = +25°C, and are not production tested.

3. At f = fMAX, address and I/O's are cycling at the maximum frequency read cycle of 1/tRC, and using "AC Test Conditions" of input levels of GND to 3V.

4. f = 0 means no address or control lines change.

5. Port "A" may be either left or right port. Port "B" is the opposite from port "A".

## DATA RETENTION CHARACTERISTICS OVER ALL TEMPERATURE RANGES (L Version Only) $(VLC = 0.2V, VHC = VCC - 0.2V)^{(4)}$

Symbol	Parameter	Test Condi	tion	Min.	Typ. <sup>(1)</sup>	Max.	Unit
Vdr	Vcc for Data Retention	Vcc = 2V		2.0	—		V
ICCDR	Data Retention Current	CE ≥ VHC	MIL.	—	100	4000	μA
		$VIN \ge VHC \text{ or } \le VLC$	COM'L.	—	100	1500	
tCDR <sup>(3)</sup>	Chip Deselect to Data Retention Time	SEM ≥ VHC		0	—		ns
tR <sup>(3)</sup>	Operation Recovery Time			trc <sup>(2)</sup>	_	_	ns
NOTES:							2683 tbl 1

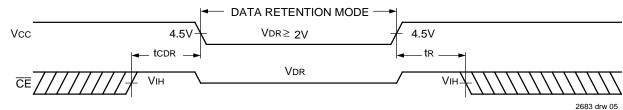
 $T_A = +25^{\circ}C$ , Vcc = 2V, and are by characterization but are not production tested. 1. 2.

tRC = Read Cycle Time

3. This parameter is guaranteed by device characterization but are not production tested.

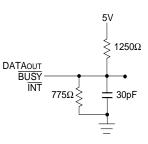
At Vcc ≤ 2.0V, input leakages are not defined.

## DATA RETENTION WAVEFORM



## **AC TEST CONDITIONS**

Input Pulse Levels	GND to 3.0V
Input Rise/Fall Times	5ns Max.
Input Timing Reference Levels	1.5V
Output Reference Levels	1.5V
Output Load	Figures 1 and 2
	2683 tbl 12



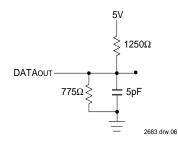


Figure 1. AC Output Test Load

Figure 2. Output Test Load (for tLz, tHz, twz, tow) \* including scope and jig.

## AC ELECTRICAL CHARACTERISTICS OVER THE **OPERATING TEMPERATURE AND SUPPLY VOLTAGE RANGE**<sup>(4)</sup>

		IDT7025X15 Com'l. Only			25X17 I. Only	IDT70	25X20	IDT70	25X25	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CY	READ CYCLE									
tRC	Read Cycle Time	15	—	17	—	20	—	25	—	ns
taa	Address Access Time	_	15	—	17		20		25	ns
tACE	Chip Enable Access Time <sup>(3)</sup>	_	15	_	17	_	20	_	25	ns
tabe	Byte Enable Access Time <sup>(3)</sup>	_	15	_	17	—	20	—	25	ns
taoe	Output Enable Access Time	—	10	—	10	—	12	—	13	ns
toн	Output Hold from Address Change	3	—	3	_	3		3	—	ns
tLZ	Output Low-Z Time <sup>(1, 2)</sup>	3	_	3	_	3	_	3	_	ns
tHZ	Output High-Z Time <sup>(1, 2)</sup>	_	10		10	_	12		15	ns
tPU	Chip Enable to Power Up Time <sup>(1,2)</sup>	0	_	0	_	0	—	0	—	ns
tPD	Chip Disable to Power Down Time <sup>(1,2)</sup>	_	15	_	17	_	20	_	25	ns
tSOP	Semaphore Flag Update Pulse (OE or SEM)	10	_	10	_	10	_	10	—	ns
tSAA	Semaphore Address Access <sup>(3)</sup>	—	15	—	17	_	20	—	25	ns

		IDT70	)25X35	IDT70	25X55	-	25X70 Only	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CY	′CLE	•						
tRC	Read Cycle Time	35	—	55	—	70	—	ns
tAA	Address Access Time	—	35	—	55		70	ns
tACE	Chip Enable Access Time <sup>(3)</sup>	_	35	_	55		70	ns
tabe	Byte Enable Access Time <sup>(3)</sup>	—	35	_	55	_	70	ns
taoe	Output Enable Access Time	_	20	—	30	_	35	ns
toн	Output Hold from Address Change	3	—	3	—	3	—	ns
tLZ	Output Low-Z Time <sup>(1, 2)</sup>	3	—	3	—	3	—	ns
tHZ	Output High-Z Time <sup>(1, 2)</sup>		15	_	25	_	30	ns
tpu	Chip Enable to Power Up Time <sup>(1,2)</sup>	0	—	0	—	0	—	ns
tPD	Chip Disable to Power Down Time <sup>(1,2)</sup>	—	35	—	50	_	50	ns
tSOP	Semaphore Flag Update Pulse (OE or SEM)	15	—	15	—	15	—	ns
tsaa	Semaphore Address Access Time <sup>(3)</sup>	—	35	_	55	_	70	ns
IOTES:								2683 tbl 1:

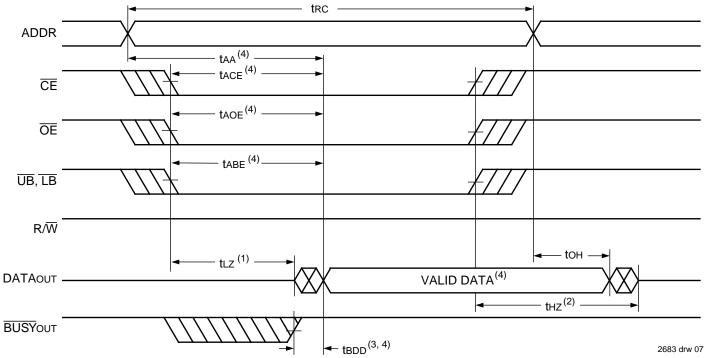
Transition is measured ±500mV from Low or High-impedance voltage with Output Test Load (Figure 2). 1.

2.

This parameter is guaranteed by device characterization, but is not production tested. To access RAM,  $\overrightarrow{CE} = VIL$ ,  $\overrightarrow{UB}$  or  $\overrightarrow{LB} = VIL$ , and  $\overrightarrow{SEM} = VIH$ . To access semephore,  $\overrightarrow{CE} = VIH$  or  $\overrightarrow{UB} \& \overrightarrow{LB} = VIH$ , and  $\overrightarrow{SEM} = VIL$ . "X" in part numbers indicates power rating (S or L). 3.

4.

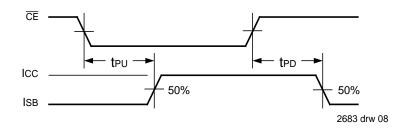
## WAVEFORM OF READ CYCLES<sup>(5)</sup>



#### NOTES:

- Timing depends on which signal is asserted last, OE, CE, LB, or UB.
   Timing depends on which signal is de-asserted first, CE, OE, LB, or UB.
- 3. tBDD delay is required only in case where opposite port is completing a write operation to the same address location for simultaneous read operations BUSY has no relation to valid output data.
- 4. Start of valid data depends on which timing becomes effective last tABE, tAOE, tACE, tAA or tBDD.
- 5.  $\overline{\text{SEM}} = \text{VIH}.$

## **TIMING OF POWER-UP POWER-DOWN**



## AC ELECTRICAL CHARACTERISTICS OVER THE OPERATING TEMPERATURE AND SUPPLY VOLTAGE<sup>(5)</sup>

		IDT702 Com'l			25X17 I. Only	IDT70	25X20	IDT7025X25		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
WRITE C										
twc	Write Cycle Time	15	—	17		20	—	25	—	ns
tew	Chip Enable to End-of-Write <sup>(3)</sup>	12	_	12	—	15	—	20	—	ns
tAW	Address Valid to End-of-Write	12	—	12	_	15	—	20	_	ns
tas	Address Set-up Time <sup>(3)</sup>	0	—	0	_	0	_	0	_	ns
tWP	Write Pulse Width	12	—	12	—	15	—	20	_	ns
tWR	Write Recovery Time	0	—	0	—	0	—	0	_	ns
tDW	Data Valid to End-of-Write	10	—	10	—	15	—	15	_	ns
tHZ	Output High-Z Time <sup>(1, 2)</sup>	—	10	—	10	—	12	—	15	ns
tdн	Data Hold Time <sup>(4)</sup>	0	—	0		0	_	0	—	ns
twz	Write Enable to Output in High-Z <sup>(1, 2)</sup>	_	10		10	_	12	_	15	ns
tow	Output Active from End-of-Write <sup>(1, 2, 4)</sup>	0	_	0	_	0	_	0	_	ns
tswrd	SEM Flag Write to Read Time	5	—	5	_	5	_	5		ns
tsps	SEM Flag Contention Window	5	—	5	—	5	-	5	-	ns

		IDT70	25X35	IDT70	25X55	-	25X70 Only	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
WRITE C	YCLE							
twc	Write Cycle Time	35	_	55	_	70	—	ns
tew	Chip Enable to End-of-Write <sup>(3)</sup>	30	_	45	_	50	—	ns
tAW	Address Valid to End-of-Write	30	_	45	_	50	_	ns
tas	Address Set-up Time <sup>(3)</sup>	0	—	0	—	0	—	ns
twp	Write Pulse Width	25	—	40	_	50	—	ns
twr	Write Recovery Time	0	—	0		0	—	ns
tDW	Data Valid to End-of-Write	15	_	30	_	40	_	ns
tHZ	Output High-Z Time <sup>(1, 2)</sup>	_	15	_	25		30	ns
tDH	Data Hold Time <sup>(4)</sup>	0	_	0	_	0	—	ns
twz	Write Enable to Output in High-Z <sup>(1, 2)</sup>	_	15	_	25	_	30	ns
tow	Output Active from End-of-Write <sup>(1, 2, 4)</sup>	0	_	0	_	0	_	ns
tSWRD	SEM Flag Write to Read Time	5	—	5	_	5	_	ns
tSPS	SEM Flag Contention Window	5	—	5	—	5	-	ns

NOTES:

1. Transition is measured ±500mV from Low or High-impedance voltage with the Output Test Load (Figure 2).

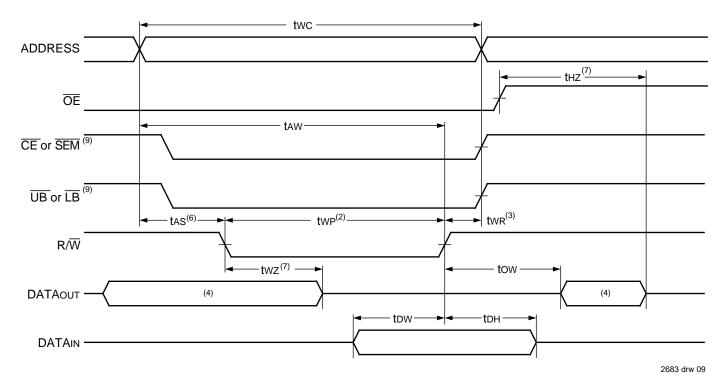
2. This parameter is guaranteed by device characterization, but is not production tested.

3. To access RAM,  $\overrightarrow{CE} = VIL$ ,  $\overrightarrow{UB}$  or  $\overrightarrow{LB} = VIL$ ,  $\overrightarrow{SEM} = VIH$ . To access semaphore,  $\overrightarrow{CE} = VIH$  or  $\overrightarrow{UB} \& \overrightarrow{LB} = VIH$ , and  $\overrightarrow{SEM} = VIL$ . Either condition must be valid for the entire tEw time.

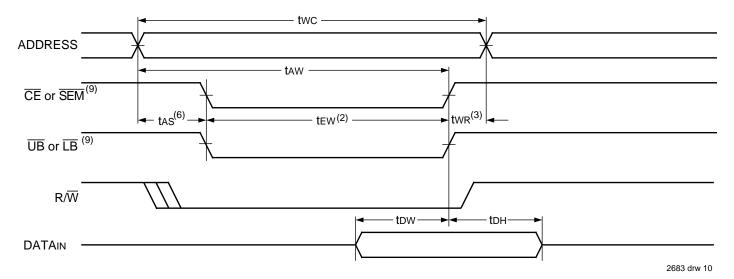
4. The specification for tDH must be met by the device supplying write data to the RAM under all operating conditions. Although tDH and tow values will vary over voltage and temperature, the actual tDH will always be smaller than the actual tow.

5. "X" in part numbers indicates power rating (S or L).

# TIMING WAVEFORM OF WRITE CYCLE NO. 1, R/W CONTROLLED TIMING<sup>(1,5,8)</sup>



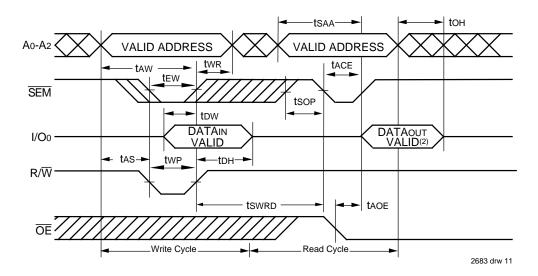
# TIMING WAVEFORM OF WRITE CYCLE NO. 2, CE, UB, LB CONTROLLED TIMING<sup>(1,5)</sup>



#### NOTES:

- 1.  $R/\overline{W}$  or  $\overline{CE}$  or  $\overline{UB}$  &  $\overline{LB}$  must be High during all address transitions.
- 2. A write occurs during the overlap (tew or twp) of a Low UB or LB and a Low CE and a Low R/W for memory array writing cycle.
- 3. twR is measured from the earlier of CE or R/W (or SEM or R/W) going High to the end-of-write cycle.
- 4. During this period, the I/O pins are in the output state and input signals must not be applied.
- 5. If the CE or SEM Low transition occurs simultaneously with or after the R/W Low transition, the outputs remain in the High-impedance state.
- 6. Timing depends on which enable signal is asserted last, <u>CE</u>, R/W, or byte control.
- 7. This parameter is guaranteed by device characterization, but is not production tested. Transition is measured +/- 500mV from steady state with Output Test Load (Figure 2).
- If OE is Low during R/W controlled write cycle, the write pulse width must be the larger of twp or (twz + tbw) to allow the I/O drivers to turn off and data to be placed on the bus for the required tbw. If OE is High during an R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified twp.
- 9. To access RAM,  $\overrightarrow{CE} = VIL$ ,  $\overrightarrow{UB}$  or  $\overrightarrow{LB} = VIL$ , and  $\overrightarrow{SEM} = VIH$ . To access Semaphore,  $\overrightarrow{CE} = VIH$  or  $\overrightarrow{UB} \& \overrightarrow{LB} = VIL$ , and  $\overrightarrow{SEM} = VIL$ . tew must be met for either condition.

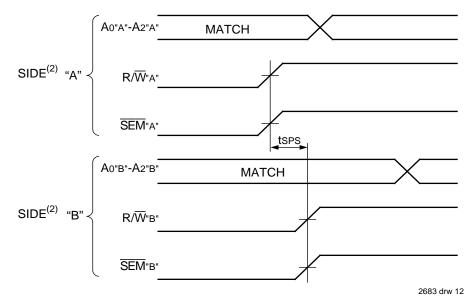
## TIMING WAVEFORM OF SEMAPHORE READ AFTER WRITE TIMING, EITHER SIDE<sup>(1)</sup>



#### NOTES:

- 1.  $\overline{CE} = VIH$  or  $\overline{UB} \& \overline{LB} = VIH$  for the duration of the above timing (both write and read cycle).
- 2. "DATAOUT VALID" represents all I/O's (I/Oo-I/O15) equal to the semaphore value.

## TIMING WAVEFORM OF SEMAPHORE WRITE CONTENTION<sup>(1,3,4)</sup>



#### NOTES:

- 1. Dor = DoL = VIL,  $\overline{CE}$ r =  $\overline{CE}$ L = VIH, or both  $\overline{UB}$  &  $\overline{LB}$  = VIH.
- 2. All timing is the same for left and right port. Port "A" may be either left or right port. Port "B" is the opposite from port "A".
- 3. This parameter is measured from R/W<sup>T</sup>A" or SEM<sup>T</sup>A" going High to R/W<sup>T</sup>B" or SEM<sup>T</sup>B" going High.
- 4. If tsps is not satisfied, there is no guarantee which side will be granted the semaphore flag.

## AC ELECTRICAL CHARACTERISTICS OVER THE **OPERATING TEMPERATURE AND SUPPLY VOLTAGE**<sup>(6)</sup>

			25X15 I Only		)25X17 'l Only	IDT70	25X20	IDT70	25X25	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
BUSY TIM	ING (M/S̄ = Vін)									
tBAA	BUSY Access Time from Address Match	-	15	—	17	_	20	_	20	ns
tBDA	BUSY Disable Time from Address Not Matched	—	15	_	17	_	20	_	20	ns
tBAC	BUSY Access Time from Chip Enable Low		15	_	17	-	20		20	ns
tBDC	BUSY Disable Time from Chip Enable High	—	15	—	17	—	17	_	17	ns
taps	Arbitration Priority Set-up Time <sup>(2)</sup>	5	_	5		5	-	5	_	ns
tBDD	BUSY Disable to Valid Data <sup>(3</sup>	_	18	-	18		30	_	30	ns
twн	Write Hold After BUSY <sup>(5)</sup>	12	—	13	—	15	-	17	_	ns
BUSY TIMI	NG (M/S̄ = Vi∟)									
twв	BUSY Input to Write <sup>(4)</sup>	0	Ι	0	_	0	_	0	_	ns
twн	Write Hold After BUSY <sup>(5)</sup>	12	_	13	_	15	—	17	_	ns
PORT-TO-I	PORT DELAY TIMING	_					-			
twdd	Write Pulse to Data Delay <sup>(1)</sup>	_	30	—	30	—	45	—	50	ns
tddd	Write Data Valid to Read Data Delay <sup>(1)</sup>	_	25	_	25	_	35	_	35	ns

		IDT70	25X35	IDT70	25X55	-	25X70 Only	
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
BUSY TIN	ЛING (M/S = Viн)	-		-	-	-		
tbaa	BUSY Access Time from Address Match	_	20		45		45	ns
tBDA	BUSY Disable Time from Address Not Matched	_	20	_	40		40	ns
tBAC	BUSY Access Time from Chip Enable Low	_	20		40		40	ns
tBDC	BUSY Disable Time from Chip Enable High		20		35		35	ns
taps	Arbitration Priority Set-up Time <sup>(2)</sup>	5	_	5		5		ns
tBDD	BUSY Disable to Valid Data <sup>(3)</sup>	_	35	—	40	—	45	ns
twн	Write Hold After BUSY <sup>(5)</sup>	25	-	25	_	25	—	ns
BUSY TIN	/ING (M/S = VIL)	•						-
twв	BUSY Input to Write <sup>(4)</sup>	0	_	0	_	0	_	ns
twн	Write Hold After BUSY <sup>(5)</sup>	25	_	25	_	25	_	ns
PORT-TO	-PORT DELAY TIMING		-					
twdd	Write Pulse to Data Delay <sup>(1)</sup>	_	60		80	_	95	ns
tDDD	Write Data Valid to Read Data Delay <sup>(1)</sup>	-	45	_	65	_	80	ns
IOTES:		-	-			-	-	2683 tbl

1. Port-to-port delay through RAM cells from writing port to reading port, refer to "Timing Waveform of Read With BUSY (M/S = VIH)" or "Timing Waveform of Write With Port-To-Port Delay  $(M/\overline{S} = VIH)$ ".

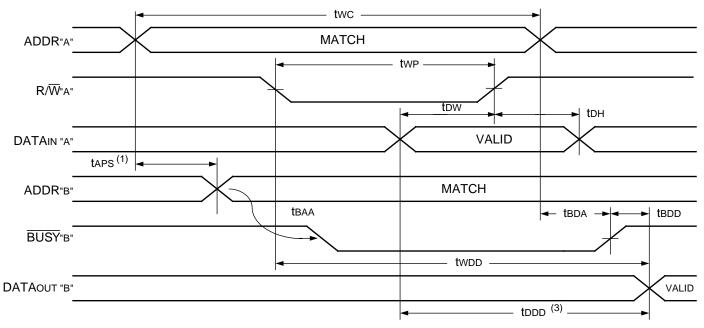
2. To ensure that the earlier of the two ports wins.

3. tBDD is a calculated parameter and is the greater of Ons, twDD - twP (actual), or tDDD - tDw (actual).

4. To ensure that the write cycle is inhibited pn Port "B" during contention with Port "A".
5. To ensure that a write cycle is completed on Port "B" after contention with Port "A".

6. "X" in part numbers indicates power rating (S or L).

# TIMING WAVEFORM OF WRITE PORT-TO-PORT READ AND $\overline{\text{BUSY}}$ (M/ $\overline{\text{S}}$ = V<sub>IH</sub>)<sup>(2,4,5)</sup>

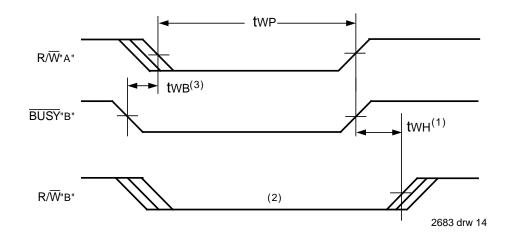


2683 drw 13

#### NOTES:

- 1. To ensure that the earlier of the two ports wins. tAPS is ignored for  $M/\overline{S} = VIL$  (slave).
- 2.  $\overline{CE}L = \overline{CE}R = VIL.$
- 3.  $\overline{OE} = V_{IL}$  for the reading port.
- 4. If M/S = VIL (slave), BUSY is an input. Then for this example BUSY<sup>∗</sup>A<sup>∗</sup> = VIH and BUSY<sup>∗</sup>B<sup>∗</sup> input is shown above.
- 5. All timing is the same for left and right ports. Port "A" may be either the left of right port. Port "B" is the opposite Port from Port "A".

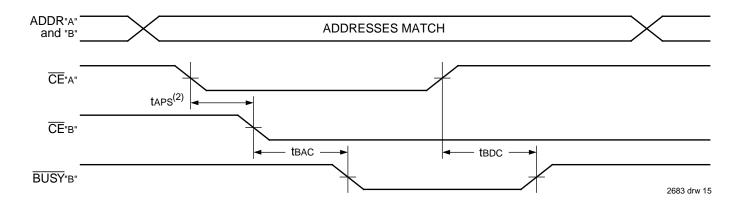
## TIMING WAVEFORM OF WRITE WITH BUSY



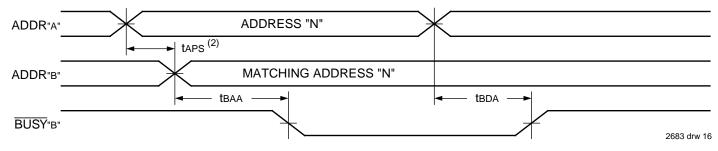
#### NOTES:

- 1. twH must be met for both BUSY input (slave) output master.
- 2. Busy is asserted on port "B" Blocking R/W"B", until BUSY"B" goes High.
- 3. twb is only for the 'Slave' Version.

# WAVEFORM OF BUSY ARBITRATION CONTROLLED BY $\overline{CE}$ TIMING (M/ $\overline{S}$ = VIH)<sup>(1)</sup>



# WAVEFORM OF BUSY ARBITRATION CYCLE CONTROLLED BY ADDRESS MATCH TIMING $(M/\overline{S} = Vih)^{(1)}$



#### NOTES:

1. All timing is the same for left and right ports. Port "A" may be either the left or right port. Port "B" is the port opposite from "A".

2. If tAPS is not satisfied, the busy signal will be asserted on one side or another but there is no guarantee on which side busy will be asserted.

## AC ELECTRICAL CHARACTERISTICS OVER THE OPERATING TEMPERATURE AND SUPPLY VOLTAGE RANGE<sup>(1)</sup>

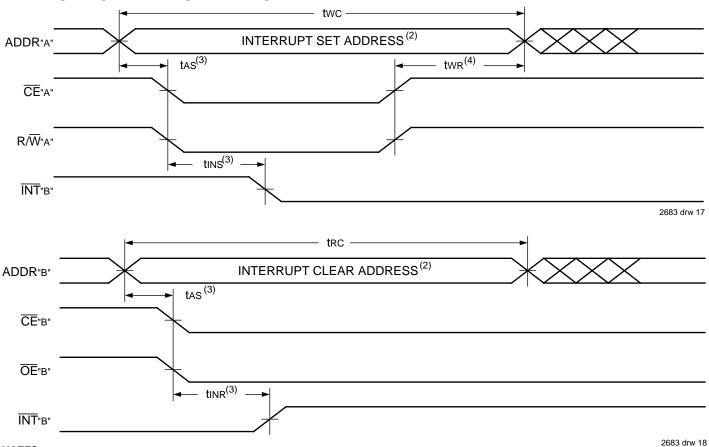
			IDT7025X15 Com'l. Only		IDT7025X17 Com'l. Only		25X20	IDT7025X25		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
INTERRU	PT TIMING									
tAS	Address Set-up Time	0	_	0		0	—	0	—	ns
twr	Write Recovery Time	0	—	0		0		0	—	ns
tins	Interrupt Set Time		15	—	15	_	20		20	ns
tinr	Interrupt Reset Time	_	15	_	15	_	20	_	20	ns

		IDT70	25X35	IDT7025X55		IDT70 Mil.		
Symbol	Parameter	Min.	Max.	Min.	Max.	Min.	Max.	Unit
INTERRU	PT TIMING							
tAS	Address Set-up Time	0	—	0	—	0	—	ns
twr	Write Recovery Time	0	_	0	—	0	_	ns
tins	Interrupt Set Time	—	25	—	40	—	50	ns
tinr	Interrupt Reset Time	—	25	—	40	—	50	ns
				•	-	-		000 11 1 40

#### NOTE:

1. "X" in part numbers indicates power rating (S or L).

## WAVEFORM OF INTERRUPT TIMING<sup>(1)</sup>



#### NOTES:

- 1. All timing is the same for left and right ports. Port "A" may be either the left or right port. Port "B" is the port opposite from "A".
- 2. See Interrupt Flag truth table.
- 3. Timing depends on which enable signal ( $\overline{CE}$  or  $R/\overline{W}$ ) is asserted last.
- 4. Timing depends on which enable signal ( $\overline{CE}$  or  $R/\overline{W}$ ) is de-asserted first.

## **TRUTH TABLES**

# TRUTH TABLE III — INTERRUPT FLAG<sup>(1)</sup>

	Le	ft Port			Right Port					
R/WL	CEL	ŌĒl	A0L-A12L	INTL	R/WR	CER	<b>OE</b> R	A0R-A12R	<b>INT</b> R	Function
L	L	Х	1FFF	Х	Х	Х	Х	Х	L <sup>(2)</sup>	Set Right INTR Flag
Х	Х	Х	Х	Х	Х	L	L	1FFF	H <sup>(3)</sup>	Reset Right INTR Flag
Х	Х	Х	Х	L <sup>(3)</sup>	L	L	Х	1FFE	Х	Set Left INT∟ Flag
Х	L	L	1FFE	H <sup>(2)</sup>	Х	Х	Х	X	Х	Reset Left INT∟ Flag

NOTES:

1. Assumes  $\overline{\text{BUSY}}_{L} = \overline{\text{BUSY}}_{R} = \text{VIH}.$ 

2. If  $\overline{\text{BUSY}}_{L} = \text{VIL}$ , then no change.

3. If  $\overline{\text{BUSYR}} = \text{VIL}$ , then no change.

4. INTR and INTL must be initialized at power-up.

## TRUTH TABLE IV — ADDRESS BUSY ARBITRATION

	Inp	outs	Out	puts	
CEL	CER	A0L-A12L A0R-A12R	BUSYL <sup>(1)</sup>	BUSY <sub>R</sub> <sup>(1)</sup>	Function
Х	Х	NO MATCH	Н	Н	Normal
н	Х	MATCH	Н	Н	Normal
Х	Н	MATCH	Н	Н	Normal
L	L	MATCH	(2)	(2)	Write Inhibit <sup>(3)</sup>

#### NOTES:

2683 tbl 18

1. Pins BUSYL and BUSYR are both outputs when the part is configured as a master. BUSY are inputs when configured as a slave. BUSYx outputs on the IDT7025 are push pull, not open drain outputs. On slaves the BUSY asserted internally inhibits write.

"L" if the inputs to the opposite port were stable prior to the address and enable inputs of this port. "H" if the inputs to the opposite port became stable after the address and enable inputs of this port. If tAPS is not met, either BUSYL or BUSYR = Low will result. BUSYL and BUSYR outputs cannot be low simultaneously.

3. Writes to the left port are internally ignored when BUSYL outputs are driving low regardless of actual logic level on the pin. Writes to the right port are internally ignored when BUSYR outputs are driving low regardless of actual logic level on the pin.

## TRUTH TABLE V — EXAMPLE OF SEMAPHORE PROCUREMENT SEQUENCE<sup>(1,2)</sup>

Functions	Do - D15 Left	Do - D15 Right	Status
No Action	1	1	Semaphore free
Left Port Writes "0" to Semaphore	0	1	Left port has semaphore token
Right Port Writes "0" to Semaphore	0	1	No change. Right side has no write access to semaphore
Left Port Writes "1" to Semaphore	1	0	Right port obtains semaphore token
Left Port Writes "0" to Semaphore	1	0	No change. Left port has no write access to semaphore
Right Port Writes "1" to Semaphore	0	1	Left port obtains semaphore token
Left Port Writes "1" to Semaphore	1	1	Semaphore free
Right Port Writes "0" to Semaphore	1	0	Right port has semaphore token
Right Port Writes "1" to Semaphore	1	1	Semaphore free
Left Port Writes "0" to Semaphore	0	1	Left port has semaphore token
Left Port Writes "1" to Semaphore	1	1	Semaphore free

#### NOTES:

1. This table denotes a sequence of events for only one of the eight semaphores on the IDT7025.

2. There are eight semaphore flags written to via I/Oo and read from all I/O's (I/Oo-I/O15). These eight semaphores are addressed by Ao - A2.

## FUNCTIONAL DESCRIPTION

The IDT7025 provides two ports with separate control, address and I/O pins that permit independent access for reads or writes to any location in memory. The IDT7025 has an automatic power down feature controlled by  $\overline{CE}$ . The  $\overline{CE}$  controls on-chip power down circuitry that permits the respective port to go into a standby mode when not selected ( $\overline{CE}$  High). When a port is enabled, access to the entire memory array is permitted.

## **INTERRUPTS**

If the user chooses to use the interrupt function, a memory location (mail box or message center) is assigned to each port. The left port interrupt flag (INTL) is asserted when the right port writes to memory location 1FFE (HEX), where a write is defined as the  $\overline{CER} = R/\overline{WR} = V_{1L}$  per the Truth Table. The left port clears the interrupt by an address location 1FFE access when  $\overline{CEL} = \overline{OEL} = V_{1L}$ ,  $R/\overline{WL}$  is a "don't care". Likewise, the right port interrupt flag (INTR) is asserted when the left port

writes to memory location 1FFF (HEX) and to clear the interrupt flag (INTR), the right port must access the memory location 1FFF. The message (16 bits) at 1FFE or 1FFF is user-defined, since it is an addressable SRAM location. If the interrupt function is not used, address locations 1FFE and 1FFF are not used as mail boxes, but as part of the random access memory. Refer to Truth Table for the interrupt operation.

## **BUSY LOGIC**

Busy Logic provides a hardware indication that both ports of the RAM have accessed the same location at the same time. It also allows one of the two accesses to proceed and signals the other side that the RAM is "Busy". The busy pin can then be used to stall the access until the operation on the other side is completed. If a write operation has been attempted from the side that receives a busy indication, the write signal is gated internally to prevent the write from proceeding.

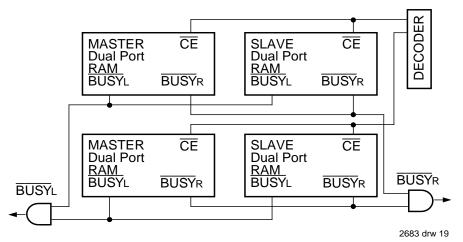


Figure 3. Busy and chip enable routing for both width and depth expansion with IDT7025 RAMs.

The use of busy logic is not required or desirable for all applications. In some cases it may be useful to logically OR the busy outputs together and use any busy indication as an interrupt source to flag the event of an illegal or illogical operation. If the write inhibit function of busy logic is not desirable, the busy logic can be disabled by placing the part in slave mode with the M/S pin. Once in slave mode the BUSY pin operates solely as a write inhibit input pin. Normal operation can be programmed by tying the BUSY pins high. If desired, unintended write operations can be prevented to a port by tying the busy pin for that port low.

The busy outputs on the IDT 7025 RAM in master mode, are push-pull type outputs and do not require pull up resistors to operate. If these RAMs are being expanded in depth, then the busy indication for the resulting array requires the use of an external AND gate.

# WIDTH EXPANSION WITH BUSY LOGIC MASTER/SLAVE ARRAYS

When expanding an IDT7025 RAM array in width while using busy logic, one master part is used to decide which side of the RAM array will receive a busy indication, and to output that indication. Any number of slaves to be addressed in the same address range as the master, use the busy signal as a write inhibit signal. Thus on the IDT7025 RAM the busy pin is an output if the part is used as a master ( $M/\overline{S}$  pin = H), and the busy pin is an input if the part used as a slave ( $M/\overline{S}$  pin = L) as shown in Figure 3.

If two or more master parts were used when expanding in width, a split decision could result with one master indicating busy on one side of the array and another master indicating busy on one other side of the array. This would inhibit the write operations from one port for part of a word and inhibit the write operations from the other port for the other part of the word.

The busy arbitration, on a master, is based on the chip enable and address signals only. It ignores whether an access is a read or write. In a master/slave array, both address and chip enable must be valid long enough for a busy flag to be output from the master before the actual write pulse can be initiated with either the  $R/\overline{W}$  signal or the byte enables. Failure to observe this timing can result in a glitched internal write inhibit signal and corrupted data in the slave.

## **SEMAPHORES**

The IDT7025 is an extremely fast Dual-Port 8K x 16 CMOS Static RAM with an additional 8 address locations dedicated to binary semaphore flags. These flags allow either processor on the left or right side of the Dual-Port RAM to claim a privilege over the other processor for functions defined by the system designer's software. As an example, the semaphore can be used by one processor to inhibit the other from accessing a portion of the Dual-Port RAM or any other shared resource.

The Dual-Port RAM features a fast access time, and both ports are completely independent of each other. This means that the activity on the left port in no way slows the access time of the right port. Both ports are identical in function to standard CMOS Static RAM and can be read from, or written to, at the same time with the only possible conflict arising from the simultaneous writing of, or a simultaneous READ/WRITE of, a non-semaphore location. Semaphores are protected against such ambiguous situations and may be used by the system program to avoid any conflicts in the non-semaphore portion of the Dual-Port RAM. These devices have an automatic power-down feature controlled by  $\overline{CE}$ , the Dual-Port RAM enable, and  $\overline{SEM}$ , the semaphore enable. The  $\overline{CE}$  and  $\overline{SEM}$ pins control on-chip power down circuitry that permits the respective port to go into standby mode when not selected. This is the condition which is shown in Truth Table where  $\overline{CE}$ and SEM are both high.

Systems which can best use the IDT7025 contain multiple processors or controllers and are typically very high-speed systems which are software controlled or software intensive. These systems can benefit from a performance increase offered by the IDT7025's hardware semaphores, which provide a lockout mechanism without requiring complex programming.

Software handshaking between processors offers the

maximum in system flexibility by permitting shared resources to be allocated in varying configurations. The IDT7025 does not use its semaphore flags to control any resources through hardware, thus allowing the system designer total flexibility in system architecture.

An advantage of using semaphores rather than the more common methods of hardware arbitration is that wait states are never incurred in either processor. This can prove to be a major advantage in very high-speed systems.

## HOW THE SEMAPHORE FLAGS WORK

The semaphore logic is a set of eight latches which are independent of the Dual-Port RAM. These latches can be used to pass a flag, or token, from one port to the other to indicate that a shared resource is in use. The semaphores provide a hardware assist for a use assignment method called "Token Passing Allocation." In this method, the state of a semaphore latch is used as a token indicating that shared resource is in use. If the left processor wants to use this resource, it requests the token by setting the latch. This processor then verifies its success in setting the latch by reading it. If it was successful, it proceeds to assume control over the shared resource. If it was not successful in setting the latch, it determines that the right side processor has set the latch first, has the token and is using the shared resource. The left processor can then either repeatedly request that semaphore's status or remove its request for that semaphore to perform another task and occasionally attempt again to gain control of the token via the set and test sequence. Once the right side has relinquished the token, the left side should succeed in gaining control.

The semaphore flags are active low. A token is requested by writing a zero into a semaphore latch and is released when the same side writes a one to that latch.

The eight semaphore flags reside within the IDT7025 in a separate memory space from the Dual-Port RAM. This address space is accessed by placing a low input on the SEM pin (which acts as a chip select for the semaphore flags) and using the other control pins (Address,  $\overline{OE}$ , and  $R/\overline{W}$ ) as they would be used in accessing a standard Static RAM. Each of the flags has a unique address which can be accessed by either side through address pins A0–A2. When accessing the semaphores, none of the other address pins has any effect.

When writing to a semaphore, only data pin Do is used. If a low level is written into an unused semaphore location, that flag will be set to a zero on that side and a one on the other side (see Table III). That semaphore can now only be modified by the side showing the zero. When a one is written into the same location from the same side, the flag will be set to a one for both sides (unless a semaphore request from the other side is pending) and then can be written to by both sides. The fact that the side which is able to write a zero into a semaphore subsequently locks out writes from the other side is what makes semaphore flags useful in interprocessor communications. (A thorough discussing on the use of this feature follows shortly.) A zero written into the same location from the other side will be stored in the semaphore request latch for that side until the semaphore is freed by the first side.

When a semaphore flag is read, its value is spread into all data bits so that a flag that is a one reads as a one in all data bits and a flag containing a zero reads as all zeros. The read value is latched into one side's output register when that side's semaphore select ( $\overline{SEM}$ ) and output enable ( $\overline{OE}$ ) signals go active. This serves to disallow the semaphore from changing state in the middle of a read cycle due to a write cycle from the other side. Because of this latch, a repeated read of a semaphore in a test loop must cause either signal ( $\overline{SEM}$  or  $\overline{OE}$ ) to go inactive or the output will never change.

A sequence WRITE/READ must be used by the semaphore in order to guarantee that no system level contention will occur. A processor requests access to shared resources by attempting to write a zero into a semaphore location. If the semaphore is already in use, the semaphore request latch will contain a zero, yet the semaphore flag will appear as one, a fact which the processor will verify by the subsequent read (see Table III). As an example, assume a processor writes a zero to the left port at a free semaphore location. On a subsequent read, the processor will verify that it has written successfully to that location and will assume control over the resource in question. Meanwhile, if a processor on the right side attempts to write a zero to the same semaphore flag it will fail, as will be verified by the fact that a one will be read from that semaphore on the right side during subsequent read. Had a sequence of READ/WRITE been used instead, system contention problems could have occurred during the gap between the read and write cycles.

It is important to note that a failed semaphore request must be followed by either repeated reads or by writing a one into the same location. The reason for this is easily understood by looking at the simple logic diagram of the semaphore flag in Figure 4. Two semaphore request latches feed into a semaphore flag. Whichever latch is first to present a zero to the semaphore flag will force its side of the semaphore flag low and the other side high. This condition will continue until a one is written to the same semaphore request latch. Should the other side's semaphore request latch have been written to a zero in the meantime, the semaphore flag will flip over to the other side as soon as a one is written into the first side's request latch. The second side's flag will now stay low until its semaphore request latch is written to a one. From this it is easy to understand that, if a semaphore is requested and the processor which requested it no longer needs the resource, the entire system can hang up until a one is written into that semaphore request latch.

The critical case of semaphore timing is when both sides request a single token by attempting to write a zero into it at the same time. The semaphore logic is specially designed to resolve this problem. If simultaneous requests are made, the logic guarantees that only one side receives the token. If one side is earlier than the other in making the request, the first side to make the request will receive the token. If both requests arrive at the same time, the assignment will be arbitrarily made to one port or the other.

One caution that should be noted when using semaphores

is that semaphores alone do not guarantee that access to a resource is secure. As with any powerful programming technique, if semaphores are misused or misinterpreted, a software error can easily happen.

Initialization of the semaphores is not automatic and must be handled via the initialization program at power-up. Since any semaphore request flag which contains a zero must be reset to a one, all semaphores on both sides should have a one written into them at initialization from both sides to assure that they will be free when needed.

## USING SEMAPHORES—SOME EXAMPLES

Perhaps the simplest application of semaphores is their application as resource markers for the IDT7025's Dual-Port RAM. Say the 8K x 16 RAM was to be divided into two 4K x 16 blocks which were to be dedicated at any one time to servicing either the left or right port. Semaphore 0 could be used to indicate the side which would control the lower section of memory, and Semaphore 1 could be defined as the indicator for the upper section of memory.

To take a resource, in this example the lower 4K of Dual-Port RAM, the processor on the left port could write and then read a zero in to Semaphore 0. If this task were successfully completed (a zero was read back rather than a one), the left processor would assume control of the lower 4K. Meanwhile the right processor was attempting to gain control of the resource after the left processor, it would read back a one in response to the zero it had attempted to write into Semaphore 0. At this point, the software could choose to try and gain control of the second 4K section by writing, then reading a zero into Semaphore 1. If it succeeded in gaining control, it would lock out the left side.

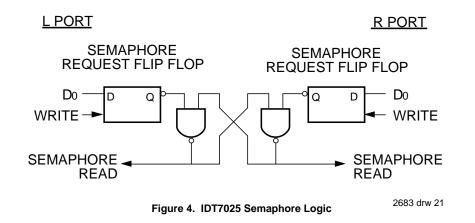
Once the left side was finished with its task, it would write a one to Semaphore 0 and may then try to gain access to Semaphore 1. If Semaphore 1 was still occupied by the right side, the left side could undo its semaphore request and perform other tasks until it was able to write, then read a zero into Semaphore 1. If the right processor performs a similar task with Semaphore 0, this protocol would allow the two processors to swap 4K blocks of Dual-Port RAM with each other.

The blocks do not have to be any particular size and can even be variable, depending upon the complexity of the software using the semaphore flags. All eight semaphores could be used to divide the Dual-Port RAM or other shared resources into eight parts. Semaphores can even be assigned different meanings on different sides rather than being given a common meaning as was shown in the example above.

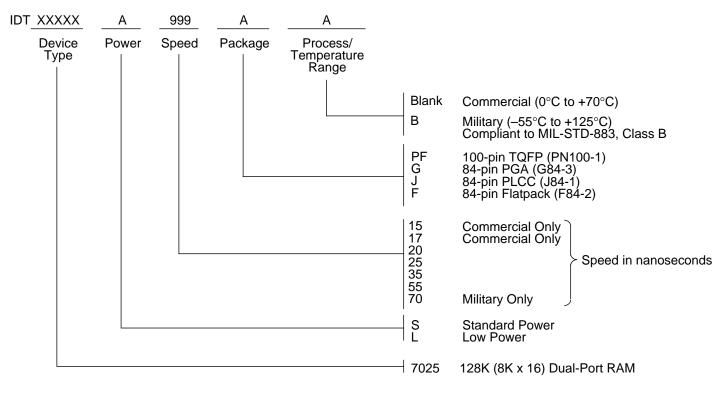
Semaphores are a useful form of arbitration in systems like disk interfaces where the CPU must be locked out of a section of memory during a transfer and the I/O device cannot tolerate any wait states. With the use of semaphores, once the two devices has determined which memory area was "off-limits" to the CPU, both the CPU and the I/O devices could access their assigned portions of memory continuously without any wait states.

Semaphores are also useful in applications where no memory "WAIT" state is available on one or both sides. Once a semaphore handshake has been performed, both processors can access their assigned RAM segments at full speed.

Another application is in the area of complex data structures. In this case, block arbitration is very important. For this application one processor may be responsible for building and updating a data structure. The other processor then reads and interprets that data structure. If the interpreting processor reads an incomplete data structure, a major error condition may exist. Therefore, some sort of arbitration must be used between the two different processors. The building processor arbitrates for the block, locks it and then is able to go in and update the data structure. When the update is completed, the data structure block is released. This allows the interpreting processor to come back and read the complete data structure, thereby guaranteeing a consistent data structure.



## **ORDERING INFORMATION**



2683 drw 21